PATENT APPLICATION

Docket Number: 071469-0305396

Client Reference: PC8014A

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

GORDON BEASE, et-al.

Group Art Unit: 1763

Application No.: 10/644,957

Examiner: Unassigned

Filed: August 21, 2003

Confirmation No.: 7598

For:

METHOD AND SYSTEM TO ENHANCE THE REMOVAL OF HIGH-K

DIELECTRIC MATERIALS

SECOND INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Applicants respectfully request the Examiner return an initialed copy of the enclosed Form PTO-1449 to Applicants with the next Office communication to indicate that the reference(s) has been considered, per MPEP § 609.

This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

The reference(s) was/were cited in a counterpart foreign application. A copy of the International Search Report is attached for the Examiner's information.

Respectfully Submitted,

Registration Number 35914

Customer Number: 00909

Date: May 6, 2004

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